

# International Rectifier

### IRF540NPbF

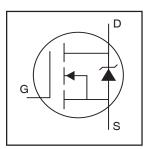
HEXFET® Power MOSFET

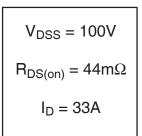
- Advanced Process Technology
- Ultra Low On-Resistance
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated
- Lead-Free

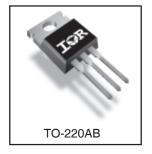
#### **Description**

Advanced HEXFET® Power MOSFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.







#### **Absolute Maximum Ratings**

	Parameter	Max.	Units	
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	33		
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	23	A	
I <sub>DM</sub>	Pulsed Drain Current ①	110		
P <sub>D</sub> @T <sub>C</sub> = 25°C	Power Dissipation	130	W	
	Linear Derating Factor	0.87	W/°C	
V <sub>GS</sub>	Gate-to-Source Voltage	± 20	V	
I <sub>AR</sub>	Avalanche Current①	16	Α	
E <sub>AR</sub>	Repetitive Avalanche Energy①	13	mJ	
dv/dt	Peak Diode Recovery dv/dt ③	7.0	V/ns	
$T_J$	Operating Junction and	-55 to + 175		
T <sub>STG</sub>	Storage Temperature Range		°C	
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)		
	Mounting torque, 6-32 or M3 srew	10 lbf•in (1.1N•m)		

#### **Thermal Resistance**

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		1.15	
R <sub>θCS</sub>	Case-to-Sink, Flat, Greased Surface	0.50		°C/W
$R_{\theta JA}$	Junction-to-Ambient		62	

#### Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

						<u> </u>
	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	100			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.12		V/°C	Reference to 25°C, I <sub>D</sub> = 1mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance			44	mΩ	V <sub>GS</sub> = 10V, I <sub>D</sub> = 16A ④
V <sub>GS(th)</sub>	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}$ , $I_D = 250\mu A$
g <sub>fs</sub>	Forward Transconductance	21			S	V <sub>DS</sub> = 50V, I <sub>D</sub> = 16A⊕
I <sub>DSS</sub>	Drain-to-Source Leakage Current			25	μA	V <sub>DS</sub> = 100V, V <sub>GS</sub> = 0V
צפטי				250		$V_{DS} = 80V, V_{GS} = 0V, T_{J} = 150^{\circ}C$
1	Gate-to-Source Forward Leakage			100	nA	V <sub>GS</sub> = 20V
I <sub>GSS</sub>	Gate-to-Source Reverse Leakage			-100	''^	V <sub>GS</sub> = -20V
Qg	Total Gate Charge			71		I <sub>D</sub> = 16A
Q <sub>gs</sub>	Gate-to-Source Charge			14	nC	$V_{DS} = 80V$
Q <sub>gd</sub>	Gate-to-Drain ("Miller") Charge			21		$V_{GS}$ = 10V, See Fig. 6 and 13
t <sub>d(on)</sub>	Turn-On Delay Time		11			V <sub>DD</sub> = 50V
t <sub>r</sub>	Rise Time		35		ns	I <sub>D</sub> = 16A
t <sub>d(off)</sub>	Turn-Off Delay Time		39		115	$R_G = 5.1\Omega$
t <sub>f</sub>	Fall Time		35			V <sub>GS</sub> = 10V, See Fig. 10 ⊕
1	Internal Drain Inductance		4.5			Between lead,
L <sub>D</sub>					nH	6mm (0.25in.)
	Internal Source Inductance		7.5	_		from package
L <sub>S</sub>						and center of die contact
C <sub>iss</sub>	Input Capacitance		1960			V <sub>GS</sub> = 0V
Coss	Output Capacitance		250			$V_{DS} = 25V$
C <sub>rss</sub>	Reverse Transfer Capacitance		40		pF	f = 1.0MHz, See Fig. 5
E <sub>AS</sub>	Single Pulse Avalanche Energy 2		700⑤	185®	mJ	I <sub>AS</sub> = 16A, L = 1.5mH

#### **Source-Drain Ratings and Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions	
Is	Continuous Source Current		33	3 A	MOSFET symbol		
	(Body Diode)				showing the		
I <sub>SM</sub>	Pulsed Source Current			110			integral reverse G
	(Body Diode)①		110	110	p-n junction diode.		
V <sub>SD</sub>	Diode Forward Voltage			1.2	V	$T_J = 25^{\circ}C$ , $I_S = 16A$ , $V_{GS} = 0V$ ④	
t <sub>rr</sub>	Reverse Recovery Time		115	170	ns	$T_J = 25^{\circ}C, I_F = 16A$	
Q <sub>rr</sub>	Reverse Recovery Charge		505	760	nC	di/dt = 100A/µs ④	
t <sub>on</sub>	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )					

#### Notes:

- Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- $\begin{tabular}{ll} \hline @ Starting $T_J=25^\circ$C, $L=1.5mH$\\ $R_G=25\Omega$, $I_{AS}=16A$. (See Figure 12) \\ \hline \end{tabular}$
- $\begin{tabular}{l} @ I_{SD} \le 16A, \ di/dt \le 340A/\mu s, \ V_{DD} \le V_{(BR)DSS}, \\ T_{J} \le 175^{\circ}C \end{tabular}$
- $\ \, \mbox{ } \mbox$
- ⑤ This is a typical value at device destruction and represents operation outside rated limits.
- $\begin{tabular}{l} \dot{\ensuremath{\text{g}}} \\ \dot$

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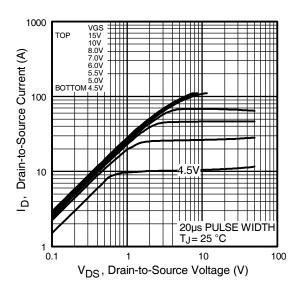


Fig 1. Typical Output Characteristics

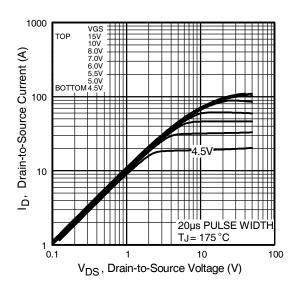


Fig 2. Typical Output Characteristics

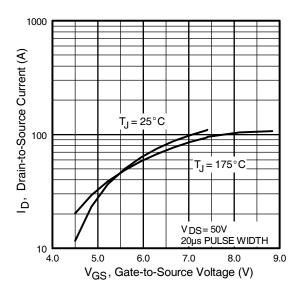


Fig 3. Typical Transfer Characteristics

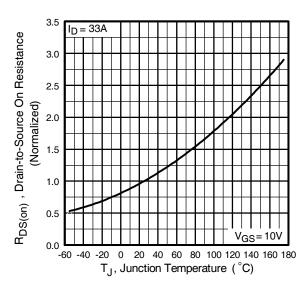
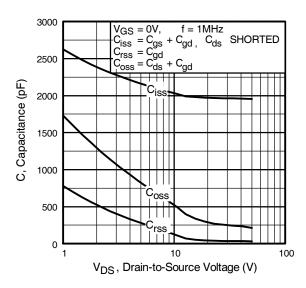
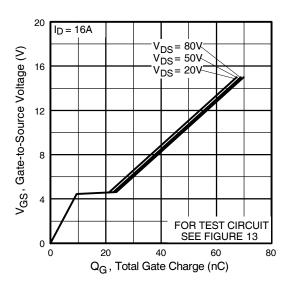


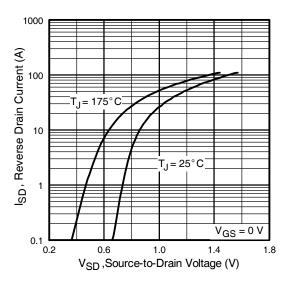
Fig 4. Normalized On-Resistance Vs. Temperature



**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage



**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage



**Fig 7.** Typical Source-Drain Diode Forward Voltage

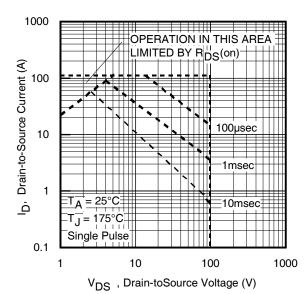
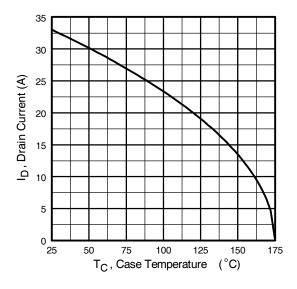


Fig 8. Maximum Safe Operating Area www.irf.com

# International TOR Rectifier

### IRF540NPbF



**Fig 9.** Maximum Drain Current Vs. Case Temperature

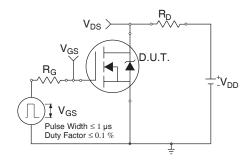


Fig 10a. Switching Time Test Circuit

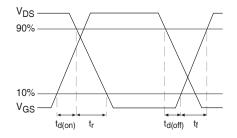


Fig 10b. Switching Time Waveforms

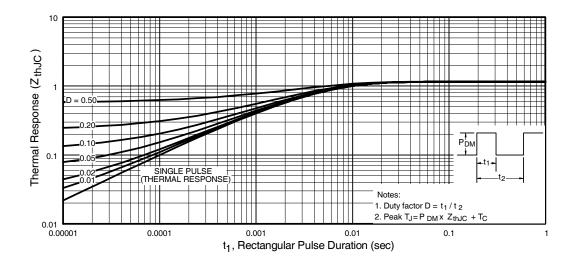


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

## International TOR Rectifier

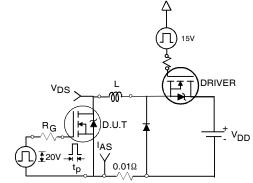


Fig 12a. Unclamped Inductive Test Circuit

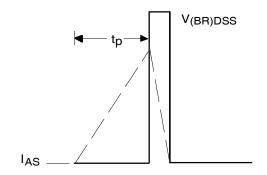


Fig 12b. Unclamped Inductive Waveforms

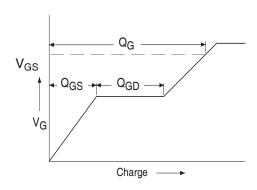
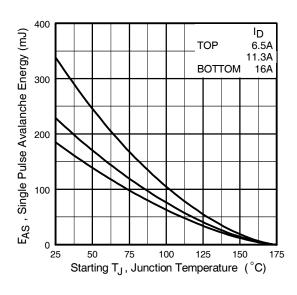


Fig 13a. Basic Gate Charge Waveform



**Fig 12c.** Maximum Avalanche Energy Vs. Drain Current

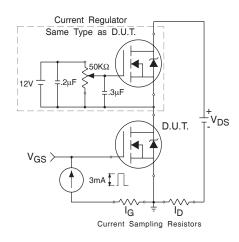
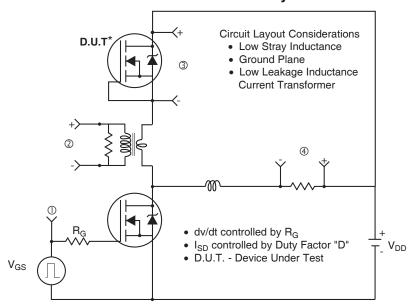
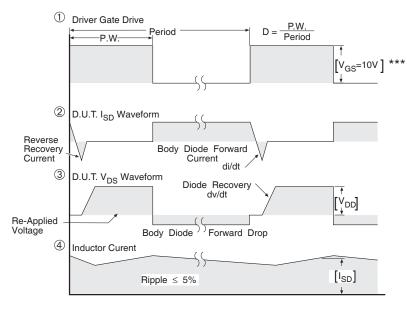


Fig 13b. Gate Charge Test Circuit

#### Peak Diode Recovery dv/dt Test Circuit



\* Reverse Polarity of D.U.T for P-Channel



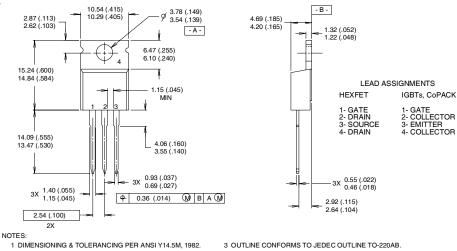
<sup>\*\*\*</sup>  $V_{GS} = 5.0V$  for Logic Level and 3V Drive Devices

Fig 14. For N-channel HEXFET® power MOSFETs

International IOR Rectifier

#### TO-220AB Package Outline

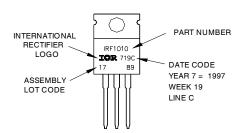
Dimensions are shown in millimeters (inches)



- 2 CONTROLLING DIMENSION: INCH
- 4 HEATSINK & LEAD MEASUREMENTS DO NOT INCLUDE BURRS.

### TO-220AB Part Marking Information

EXAMPLE: THIS IS AN IRF1010 LOT CODE 1789 ASSEMBLED ON WW 19, 1997 IN THE ASSEMBLY LINE "C" Note: "P" in assembly line position indicates "Lead-Free"



Data and specifications subject to change without notice. This product has been designed and qualified for the industrial market. Qualification Standards can be found on IR's Web site.



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Note: For the most current drawings please refer to the IR website at: <a href="http://www.irf.com/package/">http://www.irf.com/package/</a>